

Model ID **PSX307A**

Model No. NM-EFP3A

- Surface cleaning and modification of wafers and substrates improve bondability of metal and adhesion of resin.
- Increasing process number of wafers and substrates in the same time by enlarging vacuum chamber capacity improves productivity.
- Panasonic original plasma monitoring system suppresses abnormal discharge and newly introduced traceability function ensures process quality
- Flexible machine concept adapts versatile production model and supports process operation.
- Capability of $\Phi 300$ mm wafer (with/without : dicing ring) contributes to wafer level package manufacturing.

**For substrate
&
wafer level PKG**



*There are cases the options and customer's specifications don't apply for machinery directive and EMC directive

Model ID	PSX307A		
Model No.	NM-EFP3A		
Cleaning Method	Parallel plate RF back-sputtering method		
Gas for Electrical Discharge *1	Ar [Option : O ₂ , O ₂ + He]		
Power source	1-phase AC 200 / 208 / 220 / 230 / 240 \pm 10 V, 50 / 60 Hz, 6.00 kVA		
Pneumatic source	0.49 MPa, 50 L/min [A.N.R.]		
Dimension *2	W 900 mm \times D 1 150 mm \times H 1 650 mm		
Mass *3	630 kg		
Specification (Target work) *4	Substrate	Wafer with dicing ring	Wafer without dicing ring
Work Size *5	L 50 mm \times W 30 mm *6 \sim L 350 mm \times W 350 mm	$\Phi 300$ mm *7	$\Phi 300$ mm

*Please refer to the specifications on details

*Pre-confirmation by customer's works is required.

*1 : If the optional oxygen gas is selected as electric discharge gas, nitrogen gas is also required to dilute exhaust

*2 : Excluding touch panel, emergency stop switch and signal tower.

*3 : In case of full option

*4 : Please select a specification among three

*5 : Please consult us about the substrate thickness

*6 : Please contact us for the substrate with depth < 30mm

*7 : outer diameter of ring : $\Phi 380$ mm

Achieve high quality production by plasma cleaning and modification from wafer level to substrate level assembly process

Wafer Level Process

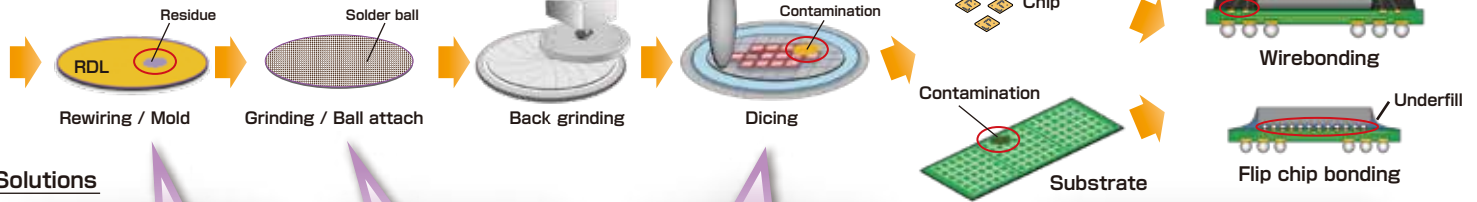
Substrate Level Process

Without ring

With ring

Substrate and Tray

From front process



Solutions

Before insulation layer coating

- Improve adhesiveness of wafer

After RDL on insulation layer

- Remove the residue after photolithography

Before ball attach

- Improve bonding quality of pad

After ball attach

- Remove the residue of stiffening resin

After dicing

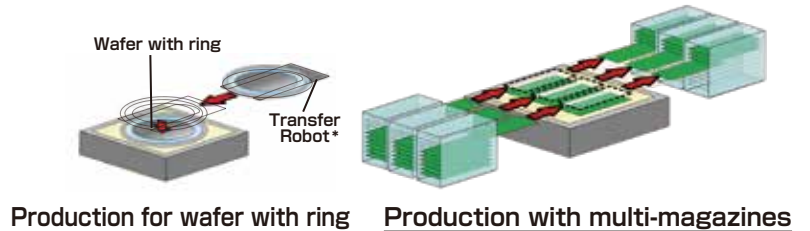
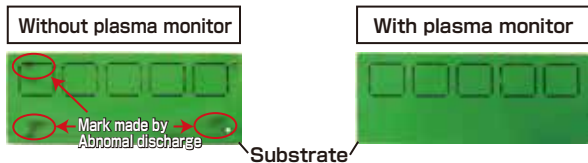
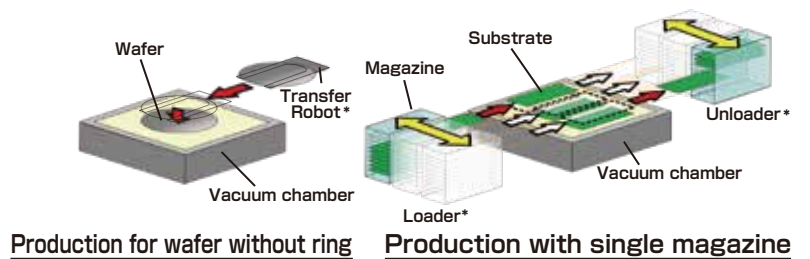
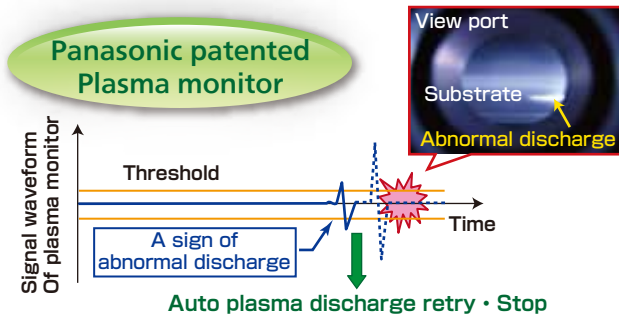
- Improve die attach ability
- Improve flip chip bonding ability

Pad cleaning / Surface activation

- Improve wirebondability
- Improve mold ability
- Improve underfill wettability

High quality management with plasma monitor

Flexibility for various type of production



- Avoid substrate damage by abnormal discharge and prevent defect substrate passing to next process
- Record the log data of monitor for each substrates (Option)

* Transfer robot, loader/unloader are prepared by customer.

⚠ Safety Cautions

- Please read the User's Manual carefully to familiarize yourself with safe and effective usage procedures.
- To ensure safety when using this equipment, all work should be performed according to that as stated in the supplied Operating Instructions. Read your operating instruction manual thoroughly.

Panasonic Group products are built with the environment in mind.

Please check the homepage for the details.
panasonic.com/global/corporate/sustainability

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